

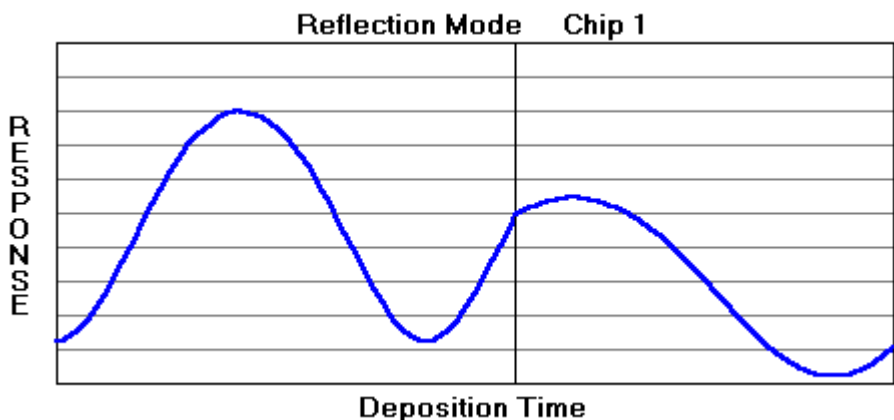
Run # _____ Operator _____ Date _____

Product _____ Customer _____

Comments _____

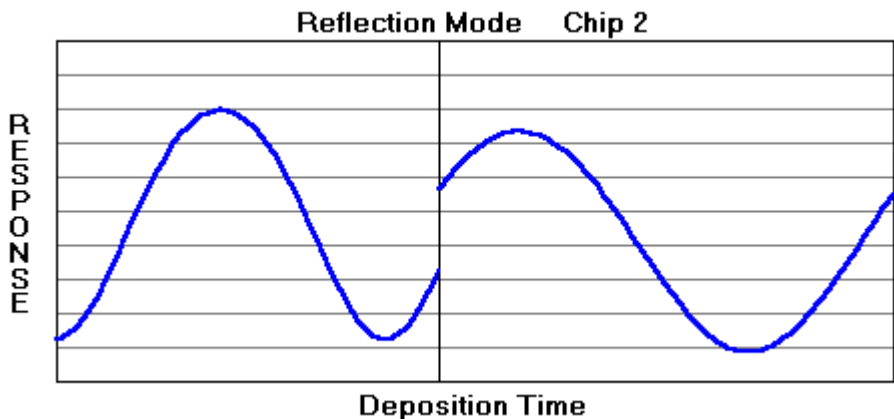
CHIP 1 (Index 1.52) Offset 0.0% Initial Setting 12.5%

Layer	Design	Wave	Signal	PAR	FULL	F/P	Crystal	OK
1-1	.41816H	600.0nm	18.4%		2.543		2.030kÅ	___
2-2	.24631L	600.0nm	14.3%	.104(i)	1.159		1.809kÅ	___



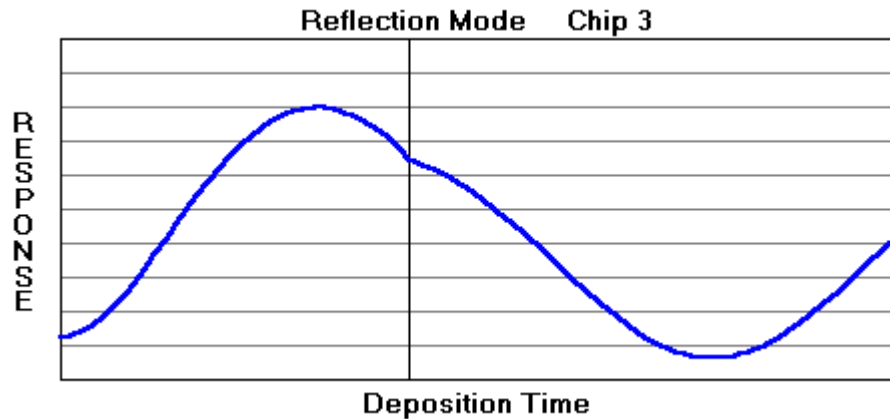
CHIP 2 (Index 1.52) Offset 0.0% Initial Setting 12.5%

Layer	Design	Wave	Signal	PAR	FULL	F/P	Crystal	OK
3-1	.33618H	520.0nm	17.5%		2.295		1.632kÅ	___
>>>> ADJUST GAIN >>>>				Offset 0.0%	Initial Setting 56.3%			
4-2	.30916L	560.0nm	6.5%	.264(i)	1.713		2.271kÅ	___



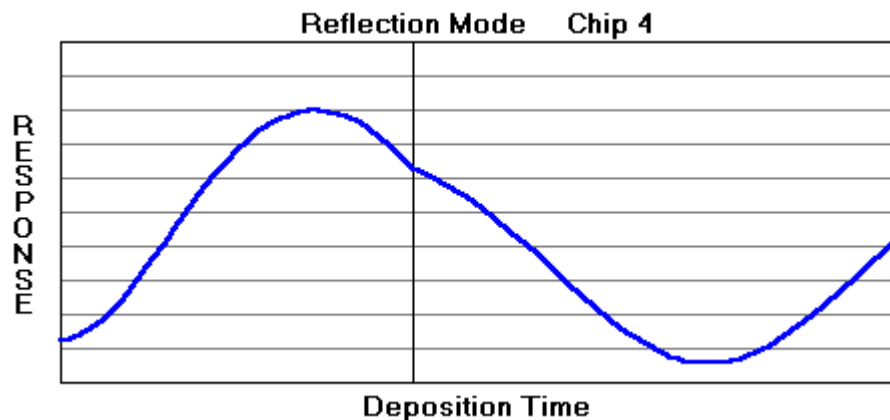
CHIP 3 (Index 1.52) Offset 0.0% Initial Setting 12.5%

Layer	Design	Wave	Signal	PAR	FULL	F/P	Crystal	OK
5-1	.26791H	700.0nm	9.2%		1.224		1.301kÅ	___
6-2	.26843L	700.0nm	8.4%	.953(d)	.583	1.611	1.972kÅ	___



CHIP 4 (Index 1.52) Offset 0.0% Initial Setting 12.5%

Layer	Design	Wave	Signal	PAR	FULL	F/P	Crystal	OK
7-1	.28503H	730.0nm	6.4%		1.254		1.384kÅ	___
8-2	.28159L	730.0nm	5.8%	.947(d)	.605	1.640	2.069kÅ	___



Printing with inserted charts is automatic. The above illustrates only one possible user-specified run-sheet format out of many.

Monitoring strategy is as important as your equipment. If you're not using optimized multi-wavelength multi-chip strategies your yields may be much less than they could be.

For help with optical monitoring contact FTG Software at tel 609 924-6222, fax 609 924-5169, e-mail ftg@compuserve.com